

1. Record Nr.	UNISA996199631103316
Titolo	1999 4th International Workshop on Statistical Metrology
Pubbl/distr/stampa	[Place of publication not identified], : Purchased from IEEE Service Center Single Publication Sales Unit, 1999
Disciplina	621.3815/2/0287
Soggetti	Semiconductors - Characterization - Statistical methods Semiconductors - Measurement Electrical Engineering Electrical & Computer Engineering Engineering & Applied Sciences
Lingua di pubblicazione	Inglese
Formato	Materiale a stampa
Livello bibliografico	Monografia
Note generali	Bibliographic Level Mode of Issuance: Monograph